

**Immedia Semiconductor, LLC
Test Photographs
FCC ID: 2AF77- H2111705**



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs Channel Separation



Test Setup



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs 20 dB Bandwidth



Test Setup



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Test Photographs
Number of Channels and Occupancy Time



Test Setup



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs
Number of Hopping Frequencies



Test Setup



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs
Peak Conducted Output Power



Test Setup



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Results No. R-6584H-1

Test Photographs
Conducted Spurious Emissions, 30 MHz to 10 GHz



Test Setup



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs
Field Strength of Spurious Emissions



EUT Configuration



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs
Field Strength of Spurious Emissions



Horizontal Antenna Polarization, 30 to 200 MHz



Vertical Antenna Polarization, 30 to 200 MHz



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Test Photographs
Field Strength of Spurious Emissions



Horizontal Antenna Polarization, 200 MHz to 1 GHz



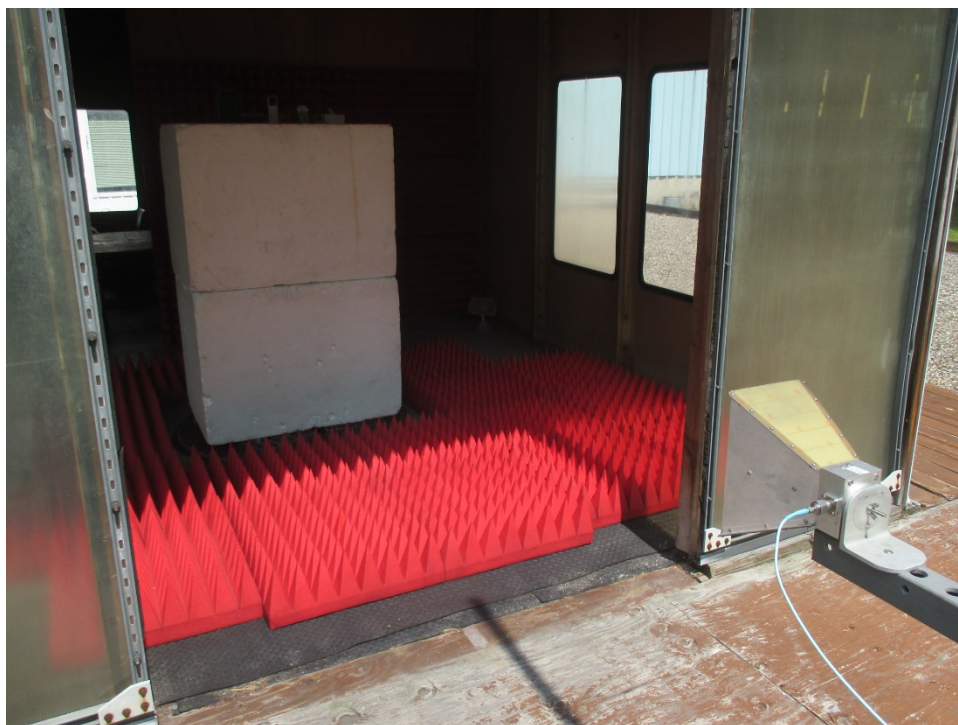
Vertical Antenna Polarization, 200 MHz to 1 GHz



Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs
Field Strength of Spurious Emissions



Horizontal Antenna Polarization, 1 GHz to 10 GHz



Vertical Antenna Polarization, 1 GHz to 10 GHz



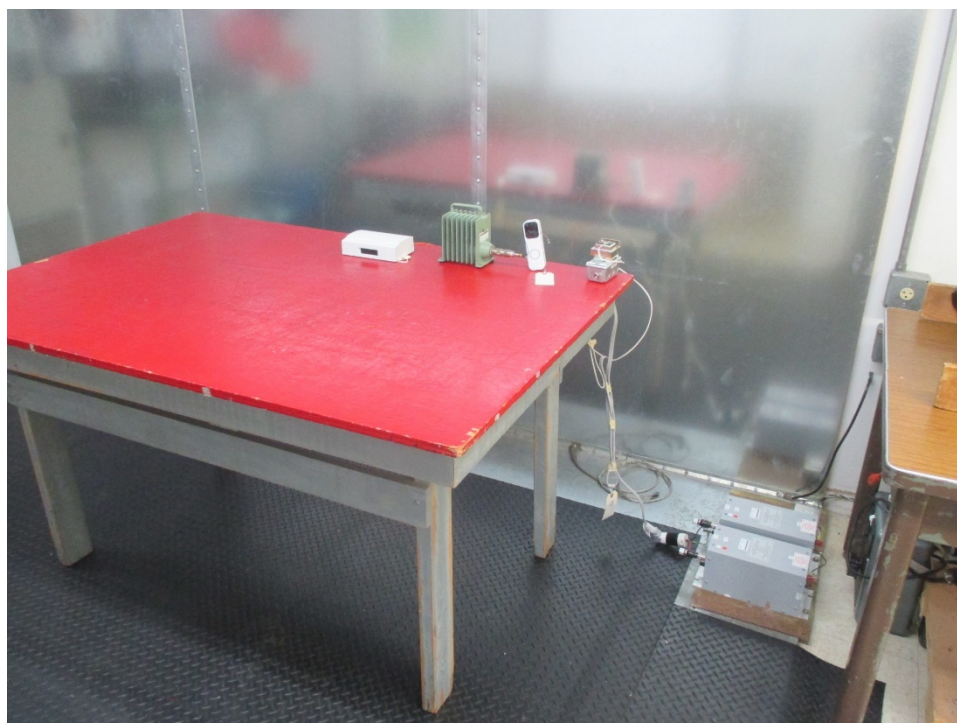
Retlif Testing Laboratories

Results No. R-6584H-1

Test Photographs Conducted Emissions



EUT Configuration



Test Setup



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